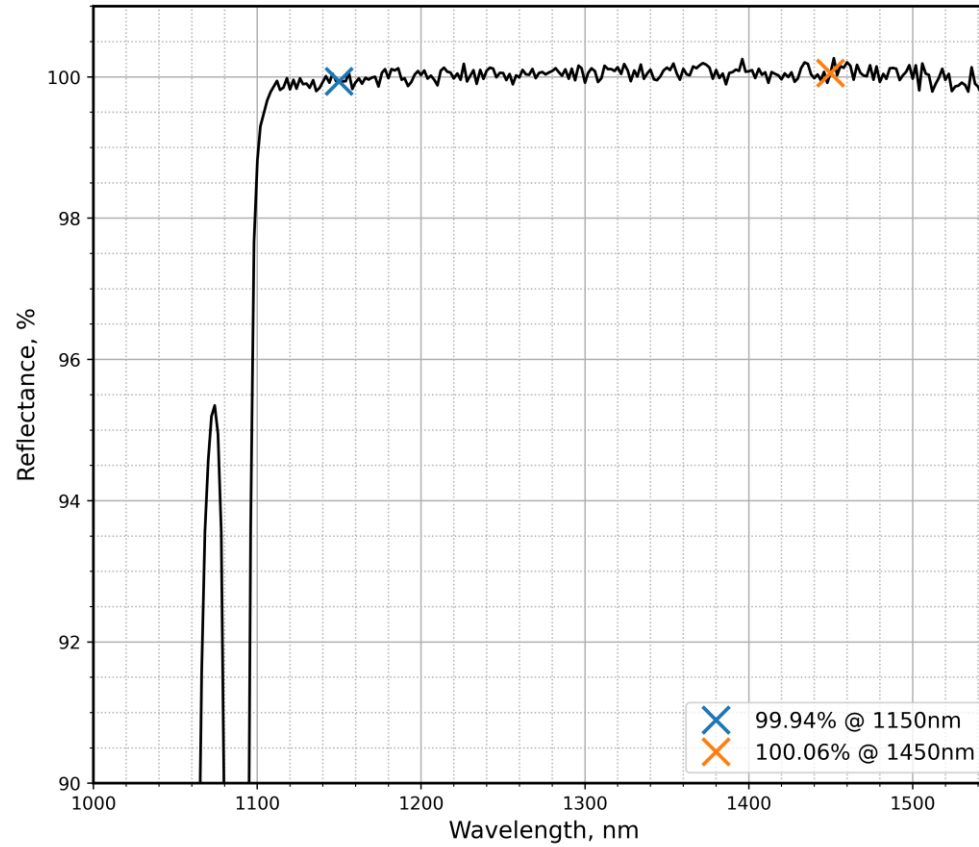


S1: SCC
S2: (arrpw marks) HRs_abs>99.95%@1150-1450 + Hrp_abs>99.5%@1130-1430 nm



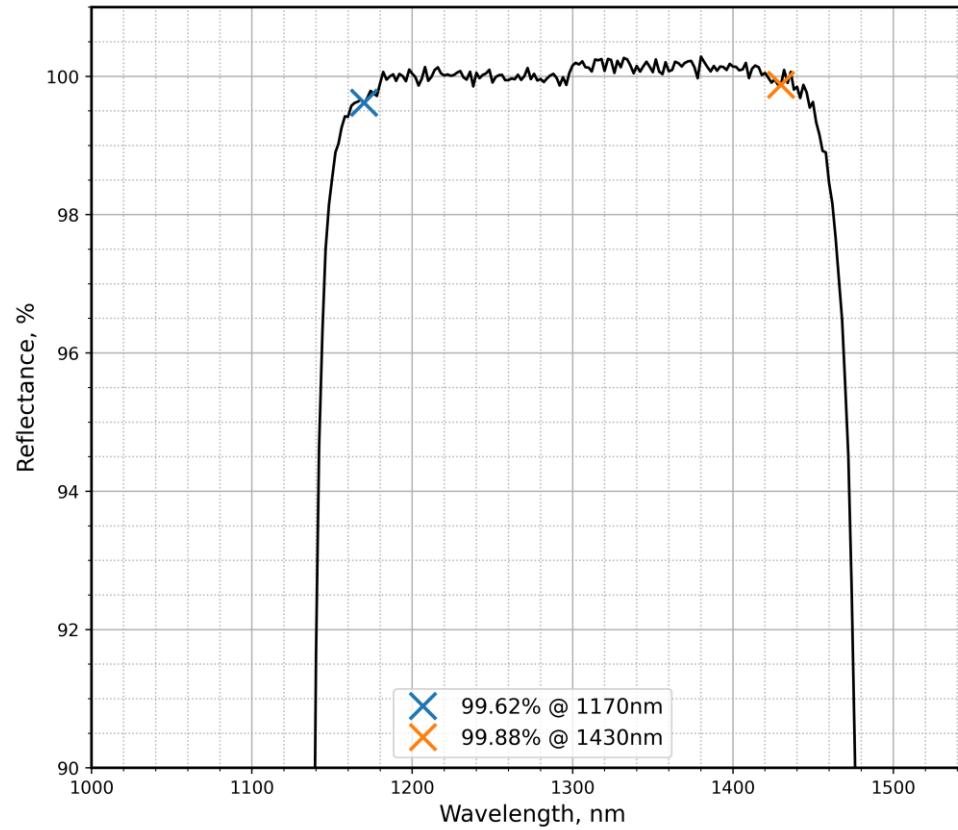
PO2205 Rs i45

Fig. 1.

SIDE MEASURED: S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: SCC
S2: (arrpw marks) HRs_abs>99.95%@1150-1450 + Hrp_abs>99.5%@1130-1430 nm



PO2205 Rp i45

Fig. 2.

SIDE MEASURED: S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

$|GDD R_s| < 50 \text{ fs}^2 @ 1150\text{-}1450 \text{ nm} + |GDD R_p| < 50 \text{ fs}^2 @ 1200\text{-}1400 \text{ nm}, AOI=45^\circ$

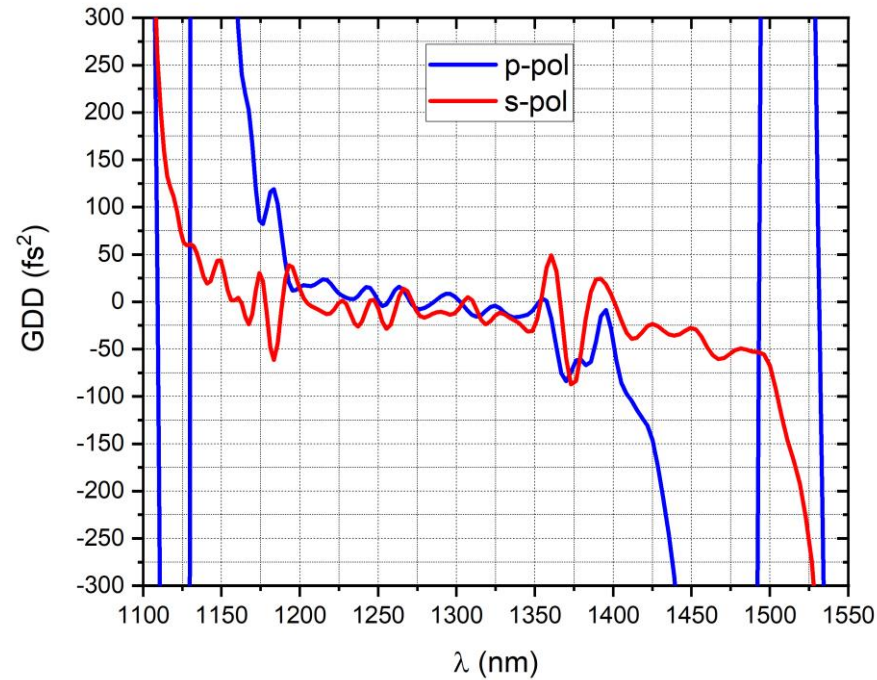


Fig. 3. GDDRsp i45

COMMENTS: GDD dip at 1380nm and ripples in the spectrum are related to the interferometric measurement errors. Shape of GDD curve confirms that position of the mirror and structure of the coating is correct.